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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Kaoru MATSUKI et al.

Group Art Unit: 2877

Application No.: 10/614,203

Filed: July 8, 2003

Docket No.: 116454

For: SURFACE PROFILE MEASURING INSTRUMENT AND SURFACE PROFILE
MEASURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. The references 1-3 were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully submitted,

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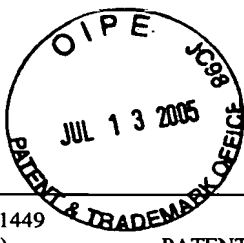
JAO:PAC/vcj

Date: July 13, 2005

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Sheet 1 of 1Form PTO-1449
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PATENT & TRADEMARK OFFICEATTY DOCKET NO.
116454APPLICATION NO.
10/614,203

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS
Kaoru MATSUKI et al.FILING DATE
July 8, 2003GROUP
2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
	1	EP 0 858 015 A1	08/12/1998	EUROPE		
	2	DE 100 00 250 A1	08/31/2000	GERMANY		
	3	DE 100 35 714 A1	07/12/2001	GERMANY		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: July 13, 2005